









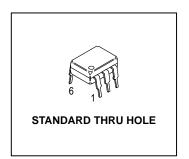








# MOC3081 **MOC3082 MOC3083**



### **COUPLER SCHEMATIC 5** 3□ CROSSING CIRCUIT 1. ANODE 2. CATHODE 3. NC 4. MAIN TERMINAL 5. SUBSTRATE DO NOT CONNECT

6. MAIN TERMINAL

## **6-Pin DIP Zero-Cross Optoisolators Triac Driver Output** (800 Volts Peak)

The MOC3081, MOC3082 and MOC3083 devices consist of gallium arsenide infrared emitting diodes optically coupled to monolithic silicon detectors performing the function of Zero Voltage Crossing bilateral triac drivers.

They are designed for use with a triac in the interface of logic systems to equipment powered from 240 Vac lines, such as solid-state relays, industrial controls, motors, solenoids and consumer appliances, etc.

- Simplifies Logic Control of 240 Vac Power
- Zero Voltage Crossing
- dv/dt of 1500 V/µs Typical, 600 V/µs Guaranteed
- To order devices that are tested and marked per VDE 0884 requirements, the suffix "V" must be included at end of part number. VDE 0884 is a test option.

#### Recommended for 240 Vac(rms) Applications:

Rating

- Solenoid/Valve Controls
- **Lighting Controls**
- Static Power Switches
- AC Motor Drives

- Temperature Controls
- E.M. Contactors
- AC Motor Starters
- Solid State Relays

Value

Unit

Symbol

#### **MAXIMUM RATINGS**

1 -		l
VR	6	Volts
lF	60	mA
PD	120	mW
	1.41	mW/°C
V <sub>DRM</sub>	800	Volts
ITSM	1	А
PD	150 1.76	mW mW/°C
VISO	7500	Vac(pk)
PD	250 2.94	mW mW/°C
TJ	-40 to +100	°C
TA	-40 to +85	°C
T <sub>stg</sub>	-40 to +150	°C
TL	260	°C
	IF PD VDRM ITSM PD VISO PD TJ TA Tstg	F   60   PD   120   1.41

<sup>1.</sup> Isolation surge voltage, VISO, is an internal device dielectric breakdown rating. For this test, Pins 1 and 2 are common, and Pins 4, 5 and 6 are common.

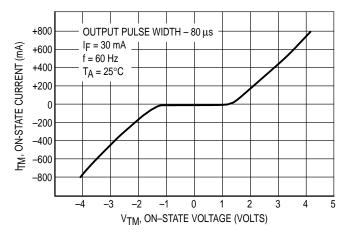


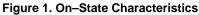
#### **ELECTRICAL CHARACTERISTICS** (T<sub>A</sub> = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Тур	Max	Unit
INPUT LED	•	•	•	•	•
Reverse Leakage Current (V <sub>R</sub> = 6 V)	I <sub>R</sub>	_	0.05	100	μΑ
Forward Voltage (I <sub>F</sub> = 30 mA)	VF	_	1.3	1.5	Volts
OUTPUT DETECTOR (I <sub>F</sub> = 0)					
Leakage with LED Off, Either Direction (V <sub>DRM</sub> = 800 V <sup>(1)</sup> )	IDRM1	_	80	500	nA
Critical Rate of Rise of Off–State Voltage(3)	dv/dt	600	1500	_	V/μs
COUPLED	-				
LED Trigger Current, Current Required to Latch Output (Main Terminal Voltage = 3 V <sup>(2)</sup> )  MOC3081  MOC3082  MOC3083	IFT	  -  -	_ _ _	15 10 5	mA
Peak On–State Voltage, Either Direction (I <sub>TM</sub> = 100 mA, I <sub>F</sub> = Rated I <sub>FT</sub> )	VTM		1.8	3	Volts
Holding Current, Either Direction	lн	_	250	_	μА
Inhibit Voltage (MT1–MT2 Voltage above which device will not trigger) (IF = Rated IFT)	VINH	_	5	20	Volts
Leakage in Inhibited State (I <sub>F</sub> = Rated I <sub>FT</sub> , V <sub>DRM</sub> = 800 V, Off State)	IDRM2	_	300	500	μА

- 1. Test voltage must be applied within dv/dt rating.
- 2. All devices are guaranteed to trigger at an IF value less than or equal to max IFT. Therefore, recommended operating IF lies between max IFT (15 mA for MOC3081, 10 mA for MOC3082, 5 mA for MOC3083) and absolute max IF (60 mA).
- 3. This is static dv/dt. See Figure 7 for test circuit. Commutating dv/dt is a function of the load-driving thyristor(s) only.

#### **TYPICAL CHARACTERISTICS**





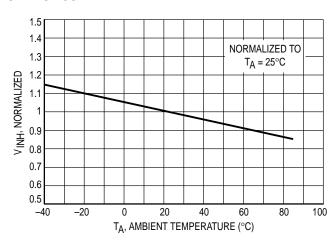


Figure 2. Inhibit Voltage versus Temperature





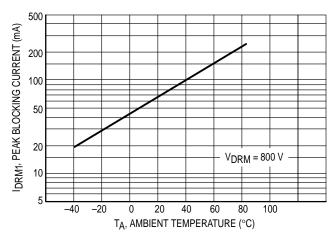


Figure 3. Leakage with LED Off versus Temperature

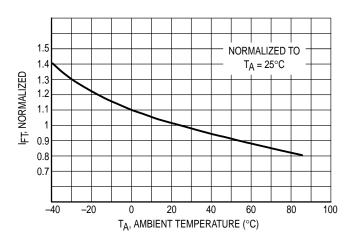


Figure 5. Trigger Current versus Temperature

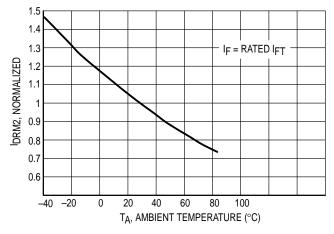


Figure 4. IDRM2, Leakage in Inhibit State versus Temperature

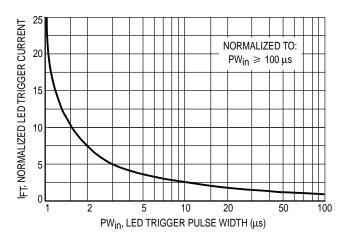
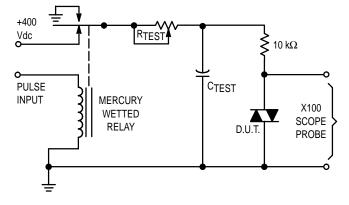


Figure 6. LED Current Required to Trigger versus LED Pulse Width

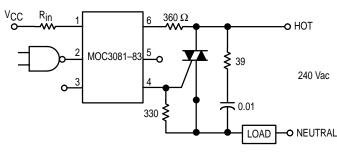


- The mercury wetted relay provides a high speed repeated pulse to the D.U.T.
- 2. 100x scope probes are used, to allow high speeds and voltages.
- 3. The worst–case condition for static dv/dt is established by triggering the D.U.T. with a normal LED input current, then removing the current. The variable RTEST allows the dv/dt to be gradually increased until the D.U.T. continues to trigger in response to the applied voltage pulse, even after the LED current has been removed. The dv/dt is then decreased until the D.U.T. stops triggering. TRC is measured at this point and recorded.



Figure 7. Static dv/dt Test Circuit

### MOC3081, MOC3082, MOC3083



\* For highly inductive loads (power factor < 0.5), change this value to 360 ohms.

Typical circuit for use when hot line switching is required. In this circuit the "hot" side of the line is switched and the load connected to the cold or neutral side. The load may be connected to either the neutral or hot line.

 $R_{\mbox{\scriptsize in}}$  is calculated so that IF is equal to the rated IFT of the part, 15 mA for the MOC3081, 10 mA for the MOC3082, and 5 mA for the MOC3083. The 39 ohm resistor and 0.01  $\mu F$  capacitor are for snubbing of the triac and may or may not be necessary depending upon the particular triac and load used.

Figure 8. Hot-Line Switching Application Circuit

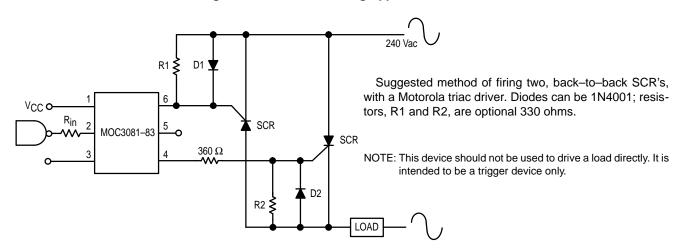
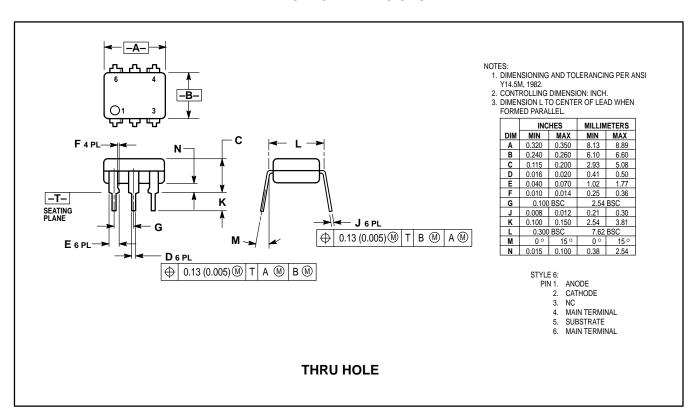
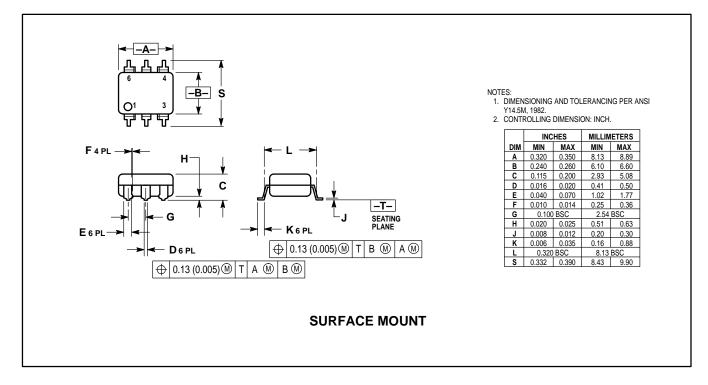


Figure 9. Inverse-Parallel SCR Driver Circuit



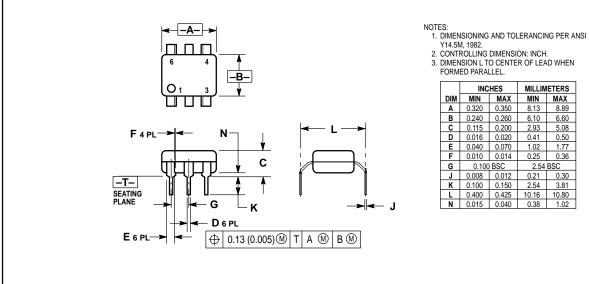
#### **PACKAGE DIMENSIONS**







# MOC3081, MOC3082, MOC3083



	INCHES		MILLIN	IETERS
DIM	MIN	MAX	MIN	MAX
Α	0.320	0.350	8.13	8.89
В	0.240	0.260	6.10	6.60
C	0.115	0.200	2.93	5.08
D	0.016	0.020	0.41	0.50
E	0.040	0.070	1.02	1.77
F	0.010	0.014	0.25	0.36
G	0.100 BSC		2.54 BSC	
J	0.008	0.012	0.21	0.30
K	0.100	0.150	2.54	3.81
L	0.400	0.425	10.16	10.80
N	0.015	0.040	0.38	1.02

0.4" LEAD SPACING



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